IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

000000000000

In re Application of:

Chen et al

Patent No.: 7.262.133 B2

Issued:

August 28, 2007

Serial No.: 10/741,824 Filed:

December 19, 2003

For:

ENHANCMENT OF

COPPER LINE

RELIABILITY USING THIN ALD TAN FILM TO CAP THE COPPER LINE

Certificate of Correction Branch Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

തതതതത Group Art Unit: 2823

Examiner:

John M

Parker

CERTIFICATE OF TRANSMISSION

I hereby certify that this correspondence is being transmitted electronically to the U.S. Patent and Trademark Office via EFS-Web on February 2.008, addressed to: Certificate of Correction Branch ner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 Date

Signature Name: Keith M. Tackett

REQUEST FOR CERTIFICATE OF CORRECTION

Attached is a Certificate of Correction for correcting several errors in the references section of the printed patent.

Applicants submit that the errors mentioned above were not by the applicant, but were made during the printing of the patent.

Respectfully submitted.

Keith M Tackett

Registration No. 32,008 PATTERSON & SHERIDAN, L.L.P. 3040 Post Oak Blvd. Suite 1500

Houston, TX 77056

Telephone: (713) 623-4844 Facsimile: (713) 623-4846 Attorney for Applicant(s)

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number (Also Form PTO-1050)

UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

PATENT NO: 7,262,133 B2 APPLICATION NO.: 10/741,824

INVENTOR(S): Ling Chen; Mei Chang

Page 1 of 1

DATED: August 28,2007

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

In the references cited, U.S. Patents Documents:

Delete: - - 4.859.307 8/1989 Nishizawa et al- -

Insert: - -4,859,625 8/1989 Nishizawa et al- -

Add .

- -US 5,904,565 5/1999 Nguyen et al- -
- -20020003403A1 1/2002 Ghosh et al- -
- -JP2001-240972 9/2001 Kazue et al- -

MAILING ADDRESS OF SENDER (Please do not use customer number below): PATTERSON & SHERIDAN 3040 Post Oak Blvd, Ste 1500 Houston, TX 77056-6582

This collection of information is required by 37 CFR 1.322, 1.323, and 1.324. The information is required to obtain or retain a benefit by the public which is to file This collection of information is required by 37 CFR 1.322, 1.323, and 1.324. The information is required to obtain or retain a benefit by the public which is to fixed by the USEPO to processal or application. Confidentiality is opermed by \$5 USL, 6.122 and \$7 CFR 1.14. This collection is estimated to start of a hour to complete, including gathering, preparing, and submitting the completed application from to the USEPTO. Time when vary depending upon the individual case. Amy comments on the amount of time by or receive to complete the form and/or suggestions for reducing this burden, should be sent to the Client immunities of the comments of the sent of the Client in the Client in the Client in the Client immunities of the Client and Tastemark Office, U.S. Department of Commence, P.O. 80x 1469, Alexandria, V. 22313-1460, D.O. NOT SEND FIELS OF COMPLETED FORMS TO THIS ADDRESS, SEND TO. Attention Certificate of Corrections Branch, Commissioner for Petalson, P.O. 80x 1469, Alexandria, V. 22313-1460.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.

United States Patent [19]

Matsumoto

[11] Patent Number: Date of Patent: ug. 22, 1989

[54] METHOD FOR EPITAXIAL GROWTH OF COMPOUND SEMICONDUCTOR USING MOCVD WITH MOLECULAR LAYER EPITAXY

[75] Inventor: Junichi Nishizawa, Miyagi-Ken Ja-pan; Toru Kurabayashi, Miyagi-Ken Japan; Hitoshi Abe, Tokyo Japan; Fumio Matsumoto, Miyagi, Japan

Research Development Corporation of [73] Assignee: Japan, Junichi Nishizawa and Oki Electric Industry Co., Ltd., Japan

[21] Appl. No.: 123,497

Nov. 20, 1987

Foreign Application Priority Data [30]

... 61-277829 Nov. 22, 1986 [JP] Japan H01L 21/205 Int. CL4 437/81: 148/DIG, 25: U.S. Cl. 148/DIG. 41; 148/DIG. 48; 148/DIG. 57;

148/DIG. 72; 148/DIG. 110; 148/DIG. 94; 156/613; 437/19; 437/111; 437/133; 437/173; 437/936; 437/942; 437/963; 427/53.1

[58] Field of Search ... 148/41, 48, 56, 65, 71, 72, 94, 110, 160, 169, 57; 156/610-614; 427/53.1, 54.1; 437/19, 81, 107, 108, 110, 111, 133, 173, 936, 942, 949, 963

References Cited [56]

U.S. PATENT DOCUMENTS

	3,867,202 3,979,235 4,058,430	2/1975 9/1976 11/1977	Esaki 357/3 Ichiki et al. 437/107 Boucher 437/84 Suntola et al. 156/611 Kuech et al. 437/81
THE PARTY OF THE P			

FOREIGN PATENT DOCUMENTS

2162206 1/1986 United Kingdom 156/611

OTHER PUBLICATIONS

Doi et al., "Stepwise Monolayer Growth of GaAs by Switched Laser Metalorganic Vapor Phase Epitaxy", Appl. Phys. Lett. 49(13), 29 Sep. 1986, pp. 785-787. Doi et al., "Growth of GaAs by Switched Laser Metalorganic Vapor Phase Epitaxy", Appl. Phys. Lett. 48(26), 30 Jun. 1986, pp. 1787-1789.

Razeghi et al., "Monolayer Epitaxy of III-V Compounds . . . ", Appl. Phys. Lett. 51(26), 28 Dec. 1987, pp. 2216-2218.

Balk et al., "Ultraviolet Induced Metal-Organic Chemical Vapor Deposition Growth of GaAs", J. Vac. Sci.

Technol. A4(3), May/Jun. 1986, pp. 711-715. Nishizawa et al., "Molecular Layer Epitaxy", J. Electrochem. Soc. May 1985, pp. 1197-1200.

Sakaki et al., "One Atomic Layer Heterointerface Fluctuations in GaAs-AlAs . . . ", Jan. 5 Appl. Phys., vol.

24, No. 6, Jun. 1985, pp. L417-L420. Pessa et al., "Atomic Layer Epitaxy . . . of cdte Films .

. ", J. Appl. Phys. 54(10), Oct. 1983, pp. 6047-6050. Usui et al., "GaAs Atomic Layer Epitaxy by Hydride VPE", Jpn. J. Appl. Phys., vol. 25, No. 3, Mar. 1986, pp. L212-L214.

Kobayashi et al., "Flow-Rate Modulation Epitaxy of GaAs", Inst. Phys. Conf. Ser. No. 79, Chapter 13, 1985, pp. 737-738.

Aoyagi et al., "Atomic-Layer Growth of GaAs by Modulated ... ", J. Vac. Sci. Technol. B5(5), Sep./Oct. 1987, pp. 1460-1464.

Bedair et al., Appl. Phys. Lett. 48(2), 13 Jan. 1986, pp. 174-176.

Nishizawa et al., "Photostimulated Molecular Layer Epitaxy", J. Vac. Sci. Technol. A4(3), May/Jun. 1986, pp. 706-710.

Primary Examiner-Brian E. Hearn Assistant Examiner-William Bunch Attorney, Agent, or Firm-Darby & Darby

A method for epitaxial growth of compound semiconductor containing three component elements, two component elements thereof being the same group elements, in which three kinds of compound gases each containing different one of the three component elements are cyclically introudced, under a predetermined pressure for a predetermined period respectively, onto a substrate enclosed in an evacuated crystal growth vessel so that a single crystal thin film of the compound semiconductor is formed on the substrate.

ABSTRACT

22 Claims, 18 Drawing Sheets

